

**FAIRCHILD**  
SEMICONDUCTOR™

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### CD4069UBC Inverter Circuits

#### General Description

The CD4069-008 consists of six inverter circuits and is manufactured using complementary MOS (CMOS) to achieve wide power supply operating range, low power consumption, high noise immunity, and symmetric controlled rise and fall times.

This device is intended for all general purpose inverter applications where the special characteristics of the MM74C901, MM74C907, and CD4049A Hex Inverter/Bufferers are not required. In those applications requiring larger noise immunity the MM74C14 or MM74C914 Hex Schmitt Trigger is suggested.

All inputs are protected from damage due to static discharge by diode clamps to  $V_{DD}$  and  $V_{SS}$ .

#### Features

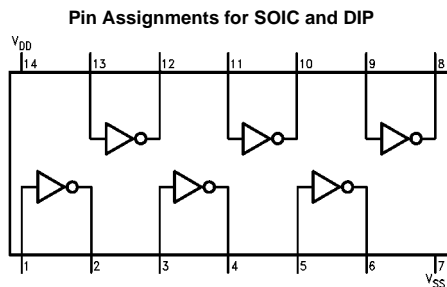
- Wide supply voltage range: 3.0V to 15V
- High noise immunity:  $0.45 V_{DD}$  typ.
- Low power TTL compatibility: Fan out of 2 driving 74L or 1 driving 74LS
- Equivalent to MM74C04

#### Ordering Code:

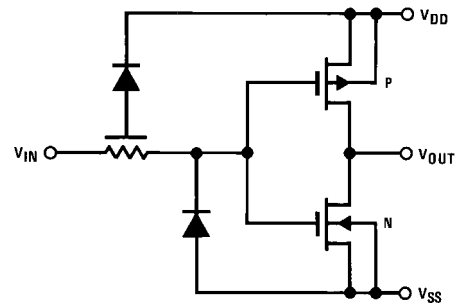
Order Number	Package Number	Package Description
CD4069-008	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow Body
CD4069-008	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
CD4069-008	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Device also available in Tape and Reel. Specify by appending suffix "X" to the ordering code.

#### Connection Diagram



#### Schematic Diagram





Absolute Maximum Ratings (Note 1)			Recommended Operating Conditions (Note 2)						
DC Supply Voltage ( $V_{DD}$ )	-0.5V to +18 $V_{DC}$		DC Supply Voltage ( $V_{DD}$ )	3V to 15 $V_{DC}$					
Input Voltage ( $V_{IN}$ )	-0.5V to $V_{DD}$ +0.5 $V_{DC}$		Input Voltage ( $V_{IN}$ )	0V to $V_{DD}$ $V_{DC}$					
Storage Temperature Range ( $T_S$ )	-65°C to +150°C		Operating Temperature Range ( $T_A$ )	-40°C to +85°C					
Power Dissipation ( $P_D$ )			<b>Note 1:</b> "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the devices should be operated at these limits. The table of "Recommended Operating Conditions" and Electrical Characteristics table provide conditions for actual device operation.						
Dual-In-Line	700 mW		<b>Note 2:</b> $V_{SS} = 0V$ unless otherwise specified.						
Small Outline	500 mW								
Lead Temperature ( $T_L$ )									
(Soldering, 10 seconds)	260°C								
DC Electrical Characteristics (Note 3)									
Symbol	Parameter	Conditions	-40°C		+25°C		+85°C		Units
			Min	Max	Min	Typ	Max	Min	
$I_{DD}$	Quiescent Device Current	$V_{DD} = 5V,$ $V_{IN} = V_{DD}$ or $V_{SS}$		1.0				7.5	$\mu A$
		$V_{DD} = 10V,$ $V_{IN} = V_{DD}$ or $V_{SS}$		2.0		2.0		15	$\mu A$
		$V_{DD} = 15V,$ $V_{IN} = V_{DD}$ or $V_{SS}$		4.0		4.0		30	$\mu A$
$V_{OL}$	LOW Level Output Voltage	$ I_O  < 1 \mu A$ $V_{DD} = 5V$		0.05	0	0.05		0.05	V
		$V_{DD} = 10V$		0.05	0	0.05		0.05	V
		$V_{DD} = 15V$		0.05	0	0.05		0.05	V
$V_{OH}$	HIGH Level Output Voltage	$ I_O  < 1 \mu A$ $V_{DD} = 5V$	4.95		4.95		4.95		V
		$V_{DD} = 10V$	9.95		9.95		9.95		V
		$V_{DD} = 15V$	14.95		14.95		14.95		V
$V_{IL}$	LOW Level Input Voltage	$ I_O  < 1 \mu A$ $V_{DD} = 5V, V_O = 4.5V$		1.0		1.0		1.0	V
		$V_{DD} = 10V, V_O = 9V$		2.0		2.0		2.0	V
		$V_{DD} = 15V, V_O = 13.5V$		3.0		3.0		3.0	V
$V_{IH}$	HIGH Level Input Voltage	$ I_O  < 1 \mu A$ $V_{DD} = 5V, V_O = 0.5V$	4.0		4.0		4.0		V
		$V_{DD} = 10V, V_O = 1V$	8.0		8.0		8.0		V
		$V_{DD} = 15V, V_O = 1.5V$	12.0		12.0		12.0		V
$I_{OL}$	LOW Level Output Current (Note 4)	$V_{DD} = 5V, V_O = 0.4V$	0.52		0.44	0.88		0.36	mA
		$V_{DD} = 10V, V_O = 0.5V$	1.3		1.1	2.25		0.9	mA
		$V_{DD} = 15V, V_O = 1.5V$	3.6		3.0	8.8		2.4	mA
$I_{OH}$	HIGH Level Output Current (Note 4)	$V_{DD} = 5V, V_O = 4.6V$	-0.52		-0.44	-0.88		-0.36	mA
		$V_{DD} = 10V, V_O = 9.5V$	-1.3		-1.1	-2.25		-0.9	mA
		$V_{DD} = 15V, V_O = 13.5V$	-3.6		-3.0	-8.8		-2.4	mA
$I_{IN}$	Input Current	$V_{DD} = 15V, V_{IN} = 0V$		-0.30		$-10^{-5}$	-0.30		$\mu A$
		$V_{DD} = 15V, V_{IN} = 15V$		0.30		$10^{-5}$	0.30		$\mu A$
<b>Note 3:</b> $V_{SS} = 0V$ unless otherwise specified. <b>Note 4:</b> $I_{OH}$ and $I_{OL}$ are tested one output at a time.									

### AC Electrical Characteristics (Note 5)

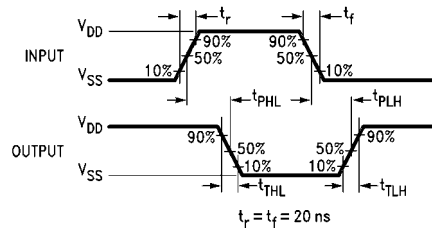
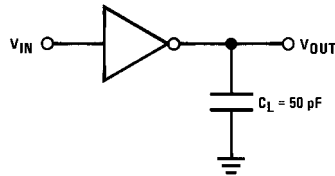
$T_A = 25^\circ\text{C}$ ,  $C_L = 50\text{ pF}$ ,  $R_L = 200\text{ k}\Omega$ ,  $t_r$  and  $t_f \leq 20\text{ ns}$ , unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$t_{PHL}$ or $t_{PLH}$	Propagation Delay Time from Input to Output	$V_{DD} = 5\text{V}$ $V_{DD} = 10\text{V}$ $V_{DD} = 15\text{V}$		50 30 25	90 60 50	ns
$t_{THL}$ or $t_{TLH}$	Transition Time	$V_{DD} = 5\text{V}$ $V_{DD} = 10\text{V}$ $V_{DD} = 15\text{V}$		80 50 40	150 100 80	ns
$C_{IN}$	Average Input Capacitance	Any Gate		6	15	pF
$C_{PD}$	Power Dissipation Capacitance	Any Gate (Note 6)		12		pF

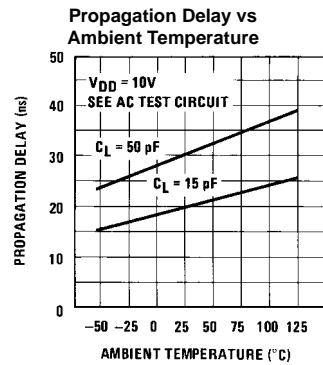
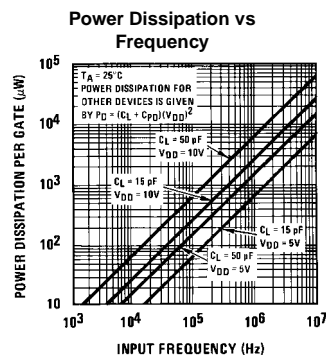
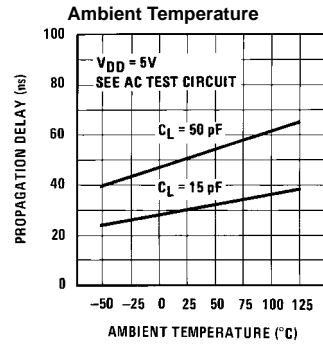
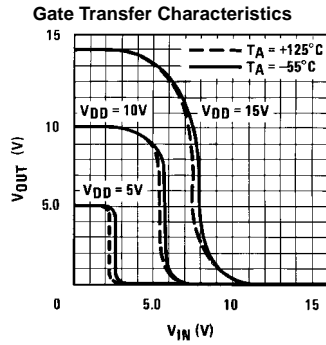
**Note 5:** AC Parameters are guaranteed by DC correlated testing.

**Note 6:**  $C_{PD}$  determines the no load AC power consumption of any CMOS device. For complete explanation, see Family Characteristics application note—AN-90.

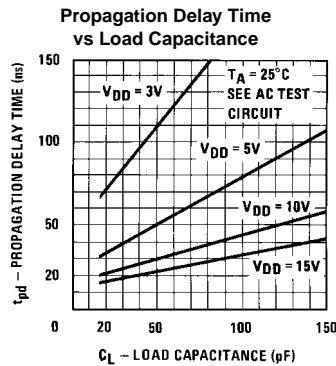
### AC Test Circuits and Switching Time Waveforms



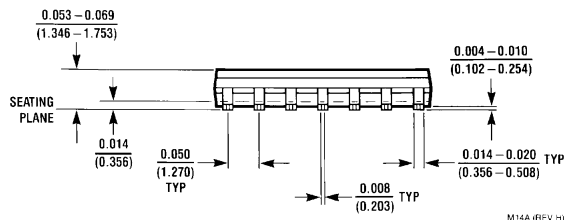
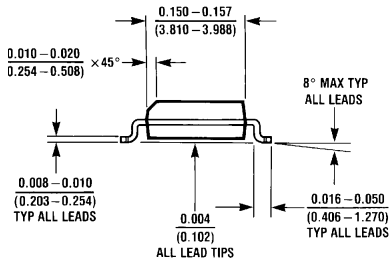
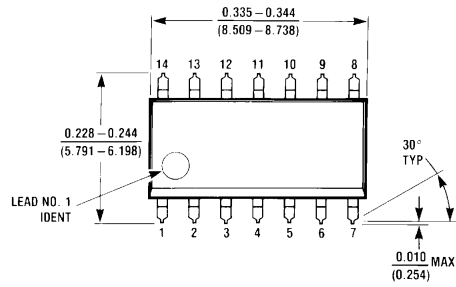
## Typical Performance Characteristics



### Propagation Delay vs

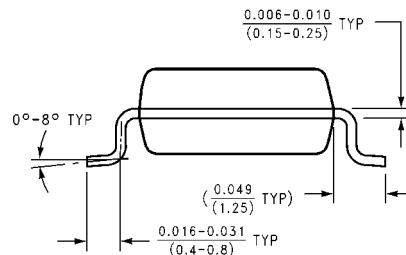
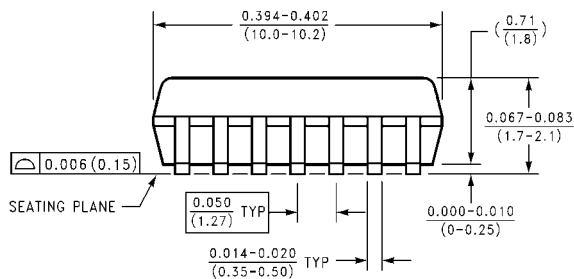
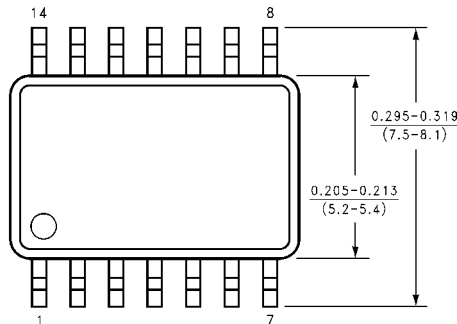


### Physical Dimensions inches (millimeters) unless otherwise noted



M14A (REV H)

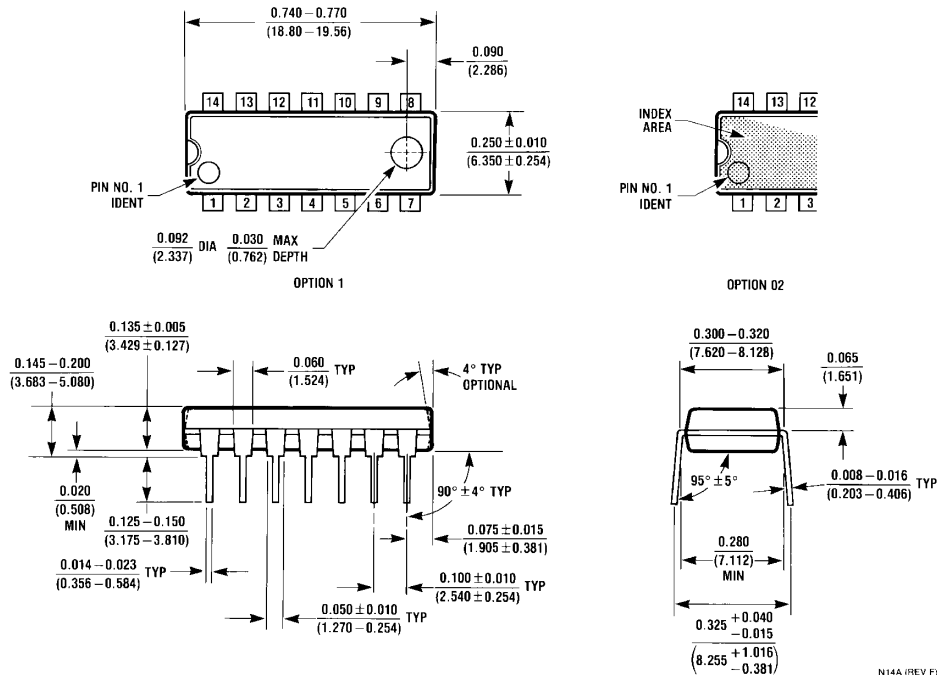
**14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow Body  
Package Number M14A**



M14D (REV B)

**14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm wide  
Package Number M14D**

### Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide Package Number N14A

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